

Search Notes

Application/Control No.

10/045,036

Examiner

Tim Phan

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

3729

29/832

SEARCHED

Class	Subclass	Date	Examiner
29	832	9/22/2003	TP
	846		
	847		
430	5		
	319		
	321		
Updated	Search	12/8/2005	TP
All	Aboce		
977	DIG.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
29	832	12/8/2005	TP
	846		
	847		
nano\$ with pigment with (photomask\$3 or mask\$3 or resist\$3..			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST Search Attached	12/8/2005	TP